

Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D
Characterisation and Imaging with Ion Beams | (smr 2856)

Contribution ID : 3

Type : **not specified**

Implementation of External Ion Beam Imaging

Monday, 26 September 2016 14:00 (1:00)

Content

Beam scanning implementation (magnetic deflection + mechanical displacement) Optimization of counting statistics and dwell time/pixel Motorized X/Y/Z sample holder Safety: large view/microscope camera with recording He gas flow Magnetic deflector (PIXE for light elements) Optimal Filters Simultaneous techniques Beam charge monitoring techniques Radiation safety with external beams: rules and procedures

Summary

Presenter(s) : CALLIGARO, Thomas (C2RMF - AGLAE Laboratory, Paris, France)

Session Classification : DAY 1